DOCUMENT CHANGE REQUEST

DCR number 527	Changes required for: General	Originator: Christian FERRE
Date: 2009/06/12	Date sent: 2009/06/12	Organisation: CNES
Status: IMPLEMENTED		

Title:	Integrated Circuits Silicon Monolithic CMOS Gate Array/Embedded Array , based on Type MH1RT		
Number:	9202/076	Issue:	2

Other documents affected:

Page:

Â§ 1.5: Maximum ratings,
Â§ 2.6: power burn-in conditions

Paragraph:

Â§ 1.5: Maximum ratings,
Â§ 2.6: power burn-in conditions

Original wording:

Proposed wording:

see attach files

Justification:

modifications asked by CNES & ESA during the yearly ESCC QML review the 2nd and 3rd of April 2009

Attachments:

DCR527att.pdf, null

Modifications:

1. Change #1 :
This change is deleted and replaced by the following:

Amend Top in Para 1.5, Max Rating table in 9202/076, to state:

// Minimum Guaranteed Operating Temperature Range // Top // -55 to +125 oC // Tamb , Note 4 //

And add new note 4 to the table:

4. For an individual ASIC design see ASIC Sheet for the actual maximum operating temperature range.

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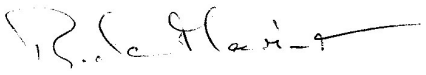
2. Change #2 :
Delete this item from DCR527 in full.

Approval signature:



Date signed:

2009-06-12

Modifications of 9202/076 Issue 2 – DCR # ??

1. Change #1 :

Maximum ratings: add the maximum junction temperature

Reason of change :
Operating temperature range [-55,+125°C] is not a m aximum rating, but an operating recommended condition.

Description of change:
In §1.5
Replace

Characteristics	Symbols	Maximum ratings	Units	Remarks
Operating temperature Range	Top	-55 to +125	°C	Tamb

By

Characteristics	Symbols	Maximum ratings	Units	Remarks
Junction temperature	Tj	175	°C	

2. Change #2 :

Add the description of power burn-in conditions.

Reason of change :
Temperature and duration being the same for all MH1RT products, it has to be stated in the Detail specification instead of in the Asic sheet. Nevertheless, specific conditions will be described in the Asic sheet.

Description of change:
In §2.6
Replace
'see Asic sheet'
by
'Unless otherwise specified in the Asic sheet, the power burn-in duration shall be 120 hours at 150°C. '

In §2.7
Replace
'Unless otherwise specified the conditions shall be as specified for power burn-in'
by
'Unless otherwise specified in the Asic sheet, the operating lifetest duration shall be 1000 hours at 150°C (equivalence MilStd883 TM 1015 with 2000hours at 125°C), except for MCGA package 2000hours at 125°C. '

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